

Description:

This N+P Channel MOSFET uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge.

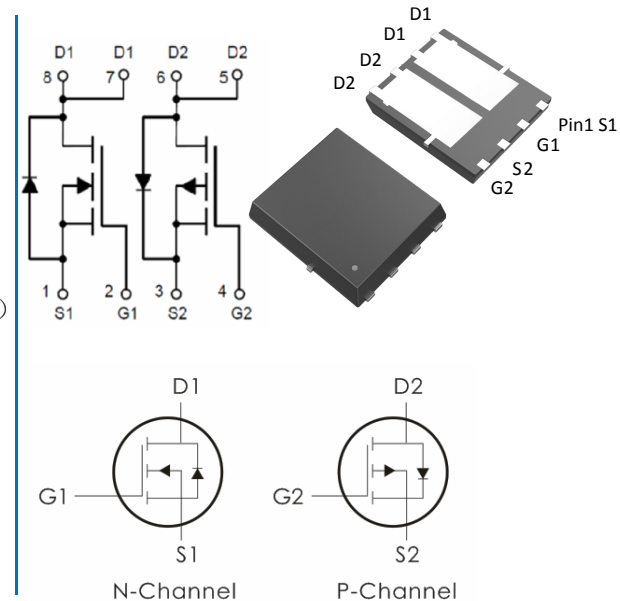
It can be used in a wide variety of applications.

Features:

N-Channel: $V_{DS}=20V, I_D=120A, R_{DS(on)} < 3.5m\Omega @ V_{GS}=4.5V$ (Typ: $2.8m\Omega$)

P-Channel: $V_{DS}=-20V, I_D=-120A, R_{DS(on)} < 4.5m\Omega @ V_{GS}=-4.5V$ (Typ: $3.6m\Omega$)

- 1) Low gate charge.
- 2) Green device available.
- 3) Advanced high cell density trench technology for ultra low $R_{DS(on)}$.
- 4) Excellent package for good heat dissipation.
- 5) MSL3



Package Marking and Ordering Information:

Part NO.	Marking	Package	Packing
DON120NP02	120NP02	DFN5*6-8D	5000 pcs/Reel

Absolute Maximum Ratings: ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	N-Channel	P-Channel	Units
V_{DS}	Drain-Source Voltage	20	-20	V
V_{GS}	Gate-Source Voltage	± 12	± 12	V
I_D	Continuous Drain Current- $T_C=25^\circ C^1$	120	-120	A
	Continuous Drain Current- $T_C=100^\circ C^1$	84	-84	
I_{DM}	Pulsed Drain Current ²	480	-480	A
E_{AS}	Single pulse avalanche energy ³	150	100	mJ
P_D	Power Dissipation - $T_C=25^\circ C$	45	39	W
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150		$^\circ C$

Thermal Characteristics:

Symbol	Parameter	N-CH	P-CH	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Cast	2.8	3.2	$^\circ C/W$

N-Channel Electrical Characteristics: ($T_C=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μ A	20	---	---	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{GS} =0V, V _{DS} =20V	---	---	1	μ A
I _{GSS}	Gate-Source Leakage Current	V _{GS} =± 12V, V _{DS} =0A	---	---	± 100	nA
On Characteristics						
V _{GS(th)}	Gate-Source Threshold Voltage	V _{GS} =V _{DS} , I _D =250 μ A	0.5	0.66	1	V
R _{DS(ON)}	Drain-Source On Resistance ⁴	V _{GS} =4.5V, I _D =20A	---	2.8	3.5	m Ω
		V _{GS} =2.5V, I _D =10A	---	3.8	4.5	m Ω
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =10V, V _{GS} =0V, f=1MHz	---	4000	---	pF
C _{oss}	Output Capacitance		---	890	---	
C _{rss}	Reverse Transfer Capacitance		---	860	---	
Switching Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DS} =10V, I _D =40A, R _{ENG} =1 Ω ,V _{GS} =4.5V	---	7.5	---	ns
t _r	Rise Time		---	25	---	ns
t _{d(off)}	Turn-Off Delay Time		---	57	---	ns
t _f	Fall Time		---	37	---	ns
Q _g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =15V, I _D =40A	---	55	---	nC
Q _{gs}	Gate-Source Charge		---	6.3	---	nC
Q _{gd}	Gate-Drain “Miller” Charge		---	25	---	nC
Drain-Source Diode Characteristics						
V _{SD}	Diode Forward Voltage	V _{GS} =0V, I _{SD} =30A	---	---	1.2	V
I _S	Continuous Drain Curren	V _D =V _G =0V	---	---	120	A
I _{SM}	Pulsed Drain Current		---	---	480	A
T _{rr}	Reverse Recovery Time	I _F =40A, T _J =25 °C	---	41	---	ns
Q _{rr}	Reverse Recovery Charge	dI/dt=100A/us	---	68	---	nC

Notes:

1. Computed continuous current assumes the condition of $T_{j,Max}$ while the actual continuous current depends on the thermal & electro-mechanical application board design
2. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
3. EAS condition : $T_J=25^{\circ}C, V_{DD}=10V, V_G=4.5V, L=0.5mH$
4. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$

N-Typical Characteristics: ($T_C=25^{\circ}C$ unless otherwise noted)

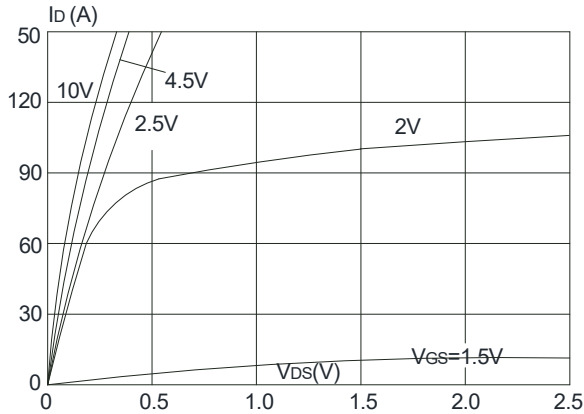


Figure1: Output Characteristics

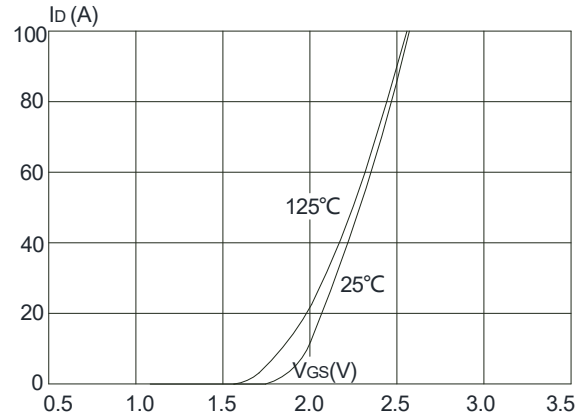


Figure 2: Typical Transfer Characteristics

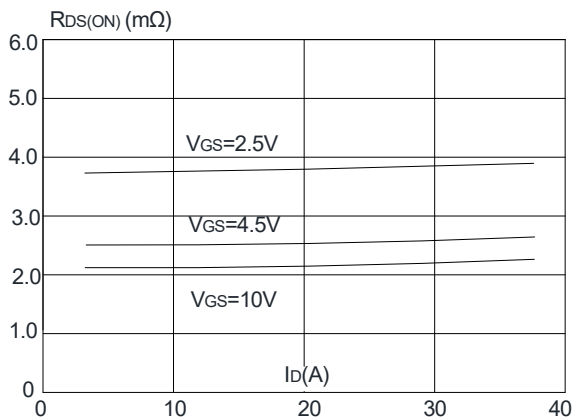


Figure 3: On-resistance vs. Drain Current

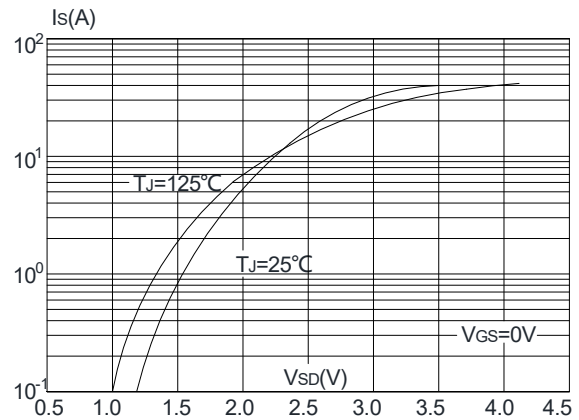


Figure 4: Body Diode Characteristics

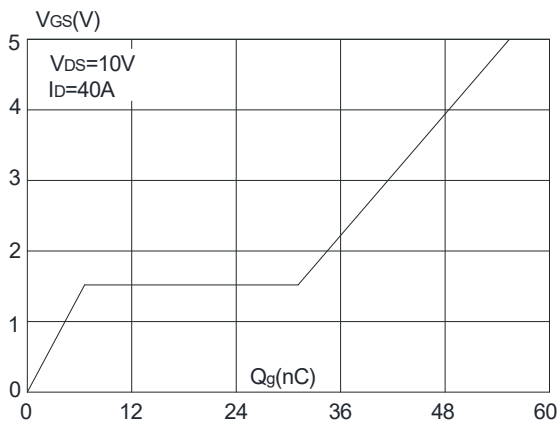


Figure 5: Gate Charge Characteristics

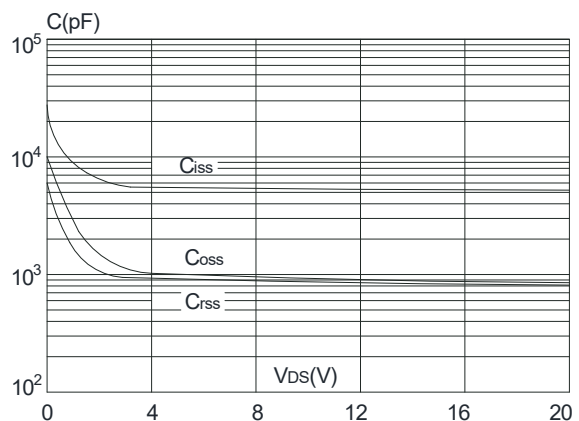


Figure 6: Capacitance Characteristics

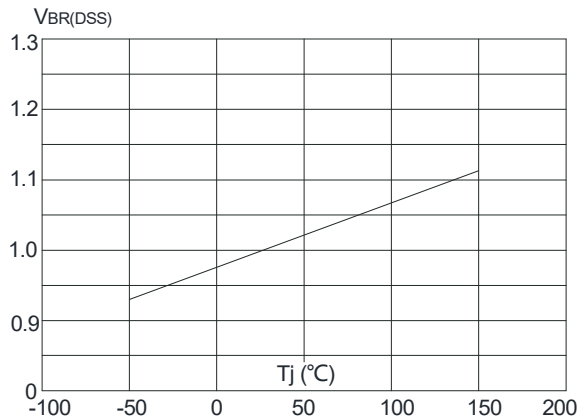


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

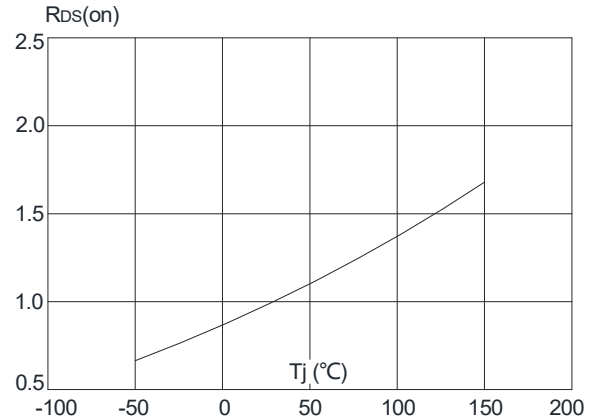


Figure 8: Normalized on Resistance vs. Junction Temperature

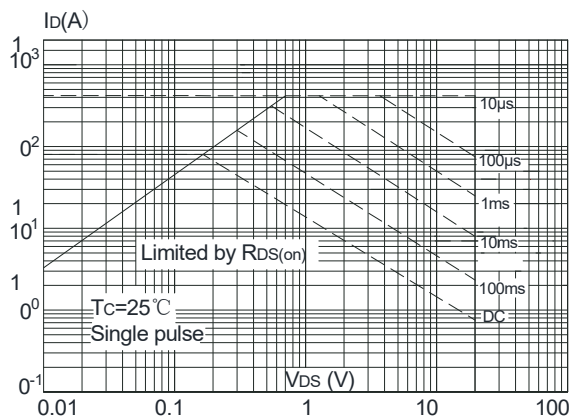


Figure 9: Maximum Safe Operating Area

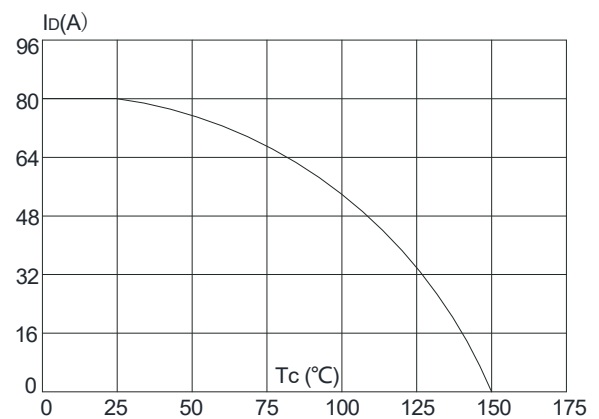


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

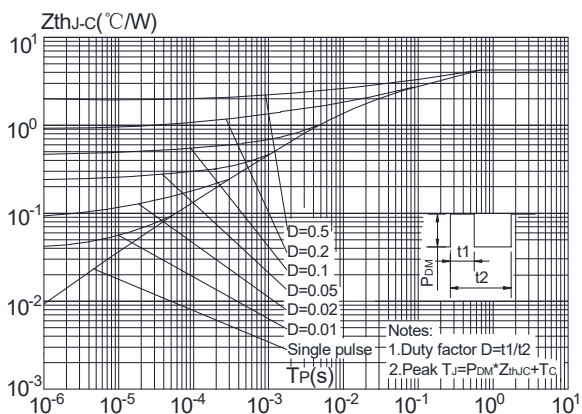


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

P-Channel Electrical Characteristics: ($T_C=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μ A	-20	---	---	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{GS} =0V, V _{DS} =-20V	---	---	-1	μ A
I _{GSS}	Gate-Source Leakage Current	V _{GS} =± 12V, V _{DS} =0A	---	---	± 100	nA
On Characteristics						
V _{GS(th)}	Gate-Source Threshold Voltage	V _{GS} =V _{DS} , I _D =250 μ A	-0.5	-0.66	-1	V
R _{DS(ON)}	Drain-Source On Resistance ⁴	V _{GS} =-4.5V, I _D =-20A	---	3.6	4.5	m Ω
		V _{GS} =-2.5V, I _D =-10A	---	4.5	5.5	
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =-10V, V _{GS} =0V, f=1MHz	---	3500	---	pF
C _{oss}	Output Capacitance		---	966	---	
C _{rss}	Reverse Transfer Capacitance		---	832	---	
Switching Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = -10V, I _D =-19A V _{GS} = -4.5V, R _{GEN} =3 Ω	---	21	---	ns
t _r	Rise Time		---	52	---	ns
t _{d(off)}	Turn-Off Delay Time		---	285	---	ns
t _f	Fall Time		---	247	---	ns
Q _g	Total Gate Charge	V _{GS} =-4.5V, V _{DS} =-10V, I _D =-19A	---	48	---	nC
Q _{gs}	Gate-Source Charge		---	7	---	nC
Q _{gd}	Gate-Drain “Miller” Charge		---	19	---	nC
Drain-Source Diode Characteristics						
I _S	Continuous Drain to Source Diode	V _D =V _G =0V	---	---	-120	A
I _{SM}	Pulsed Drain to Source Diode		---	---	-480	---
T _{rr}	Reverse Recovery Time	I _F =-19A, T _J =25 °C	---	243	---	ns
Q _{rr}	Reverse Recovery Charge	dI/dt=100A/us	---	591	---	nC
V _{SD}	Source-Drain Diode Forward Voltage	V _{GS} =0V, I _S =-19A	---	---	-1.2	V

Notes:

1. Computed continuous current assumes the condition of $T_{j,Max}$ while the actual continuous current depends on the thermal & electro-mechanical application board design
2. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
3. EAS condition : $T_J=25^{\circ}C, V_{DD}=-10V, V_G=-4.5V, L=1mH$
4. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$

Test Circuit & Waveform

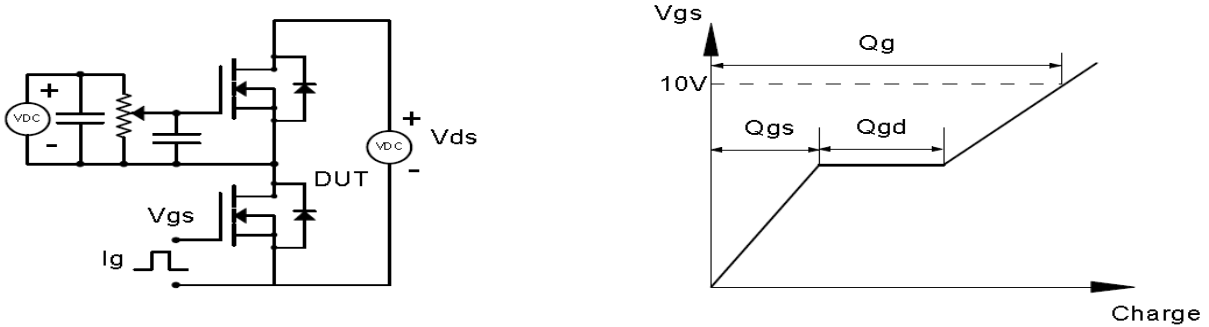


Figure1: Gate Charge Test Circuit & Waveform

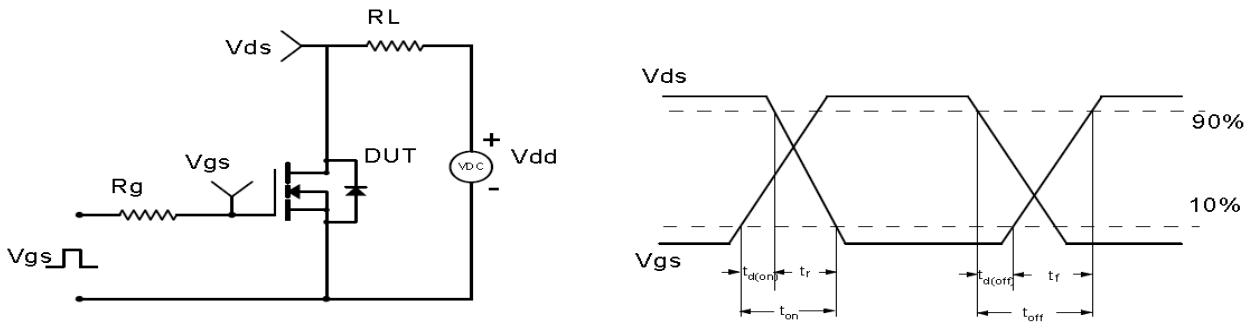


Figure 2: Resistive Switching Test Circuit & Waveforms

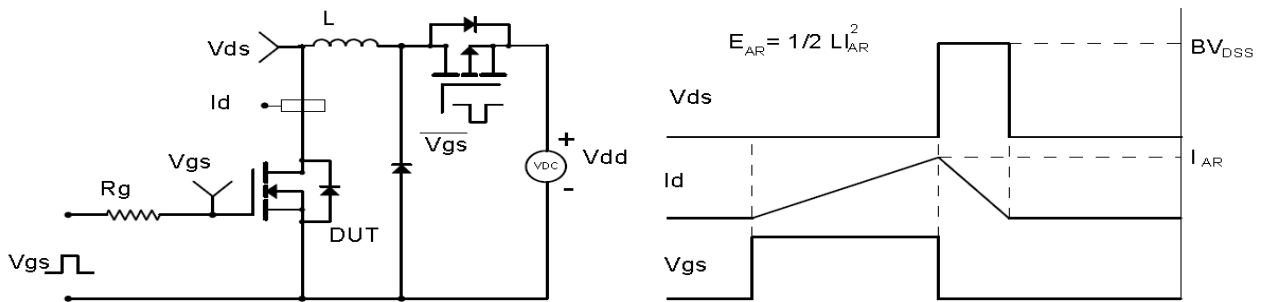


Figure 3: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

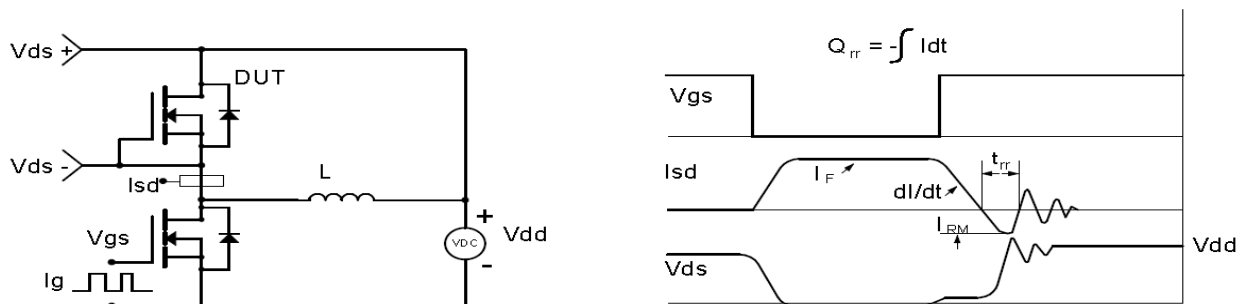
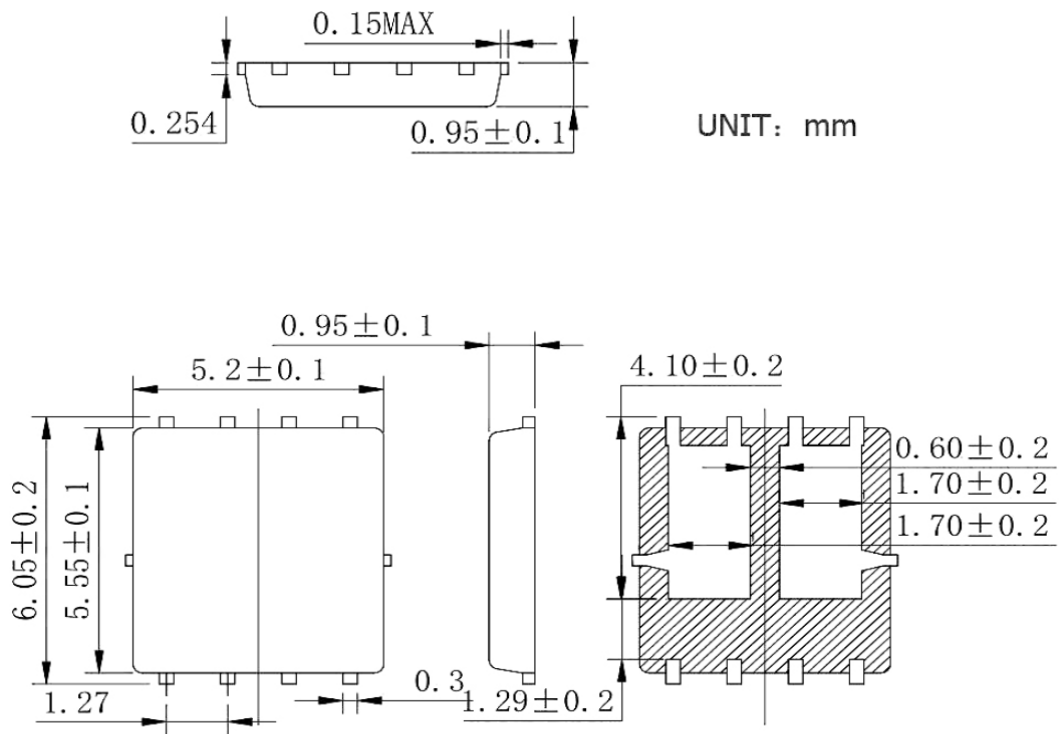


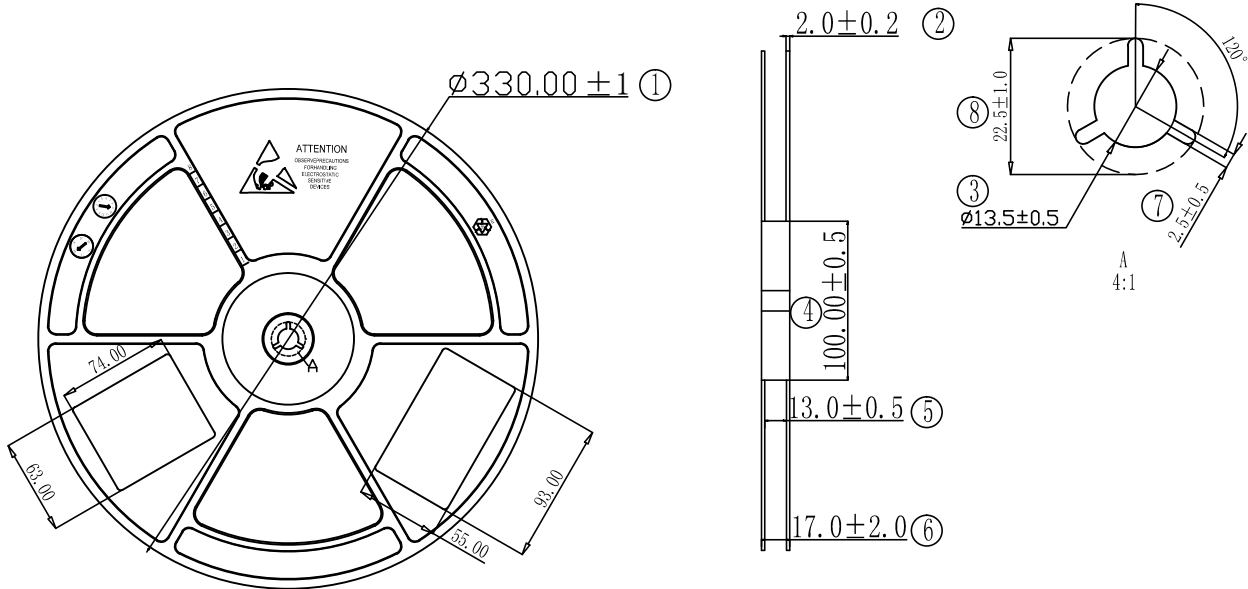
Figure 4: Diode Recovery Test Circuit & Waveforms

DFN5×6-8D Package Information:

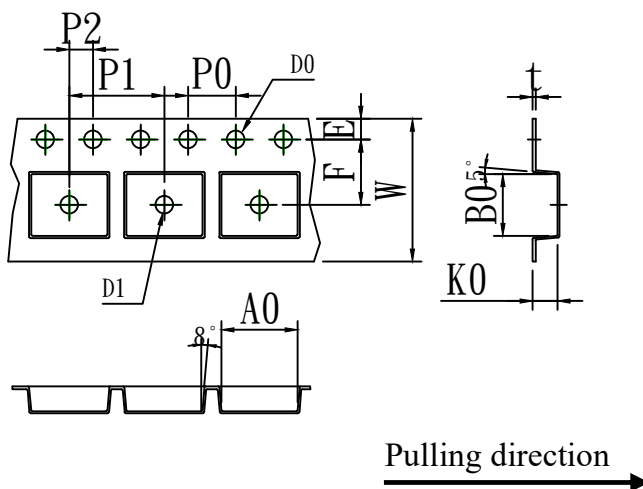


Tape & Reel Information

Dimensions in mm



Symbol	A0	B0	K0	D0	D1	P0	P1	10*P0
Spec	6.15±0.10	5.40±0.10	1.30±0.10	1.55±0.10	1.55±0.10	4.00±0.10	8.00±0.10	40.00±0.10
Symbol	W	E	F	P2	t			
Spec	12.00±0.10	1.75±0.10	5.50±0.10	2.00±0.10	0.20±0.05			



Marking Information:

①. Doingter LOGO

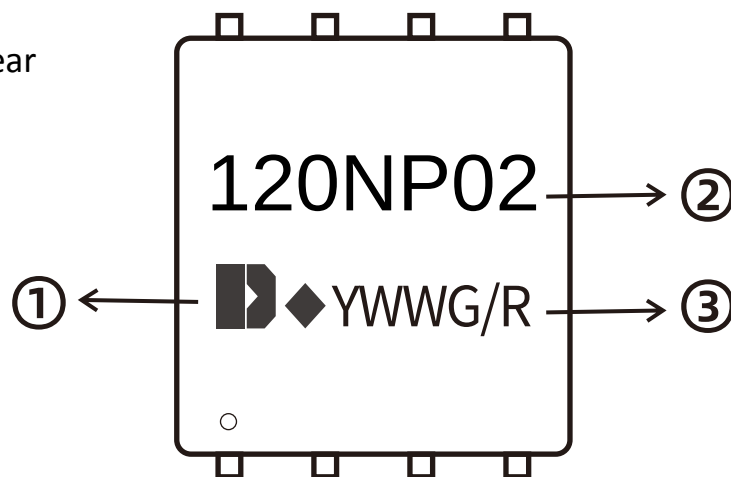
②. Part NO.

③. Date Code(YWWG / R)

Y : Year Code , last digit of the year

WW : Week Code(01-53)

G/R : G(Green) /R(Lead Free)



Previous Version

Version	Date	Subjects (major changes since last revision)
1.0	2025-04-02	Release of final version

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